

**Notice of References Cited**

Application/Control No.

10/723,591

Applicant(s)/Patent Under  
Reexamination  
CHUAH ET AL.

Examiner

JOHN J. LEE

Art Unit

2618

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*	B	US-2003/0153346	08-2003	Kim et al.	455/522
*	C	US-2004/0131026	07-2004	Kim et al.	370/328
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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